



AG 2881  
PATENT  
Docket No.: 29273/559  
IFW

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

APPLICANTS: Yuko Iwabuchi et al.

APPLICATION NO.: 10/083,481

FILED: February 27, 2002

FOR: METHOD AND APPARATUS OF AN INSPECTION SYSTEM  
USING AN ELECTRON BEAM

ART UNIT: 2881

EXAMINER: Jack Berman

COMMISSIONER FOR PATENTS  
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**RESPONSE TO OFFICE ACTION**

S I R:

In response to the October 8, 2004 Office Action, Applicants submit this response.